New results from T2K experiment

Ken Sakashita for T2K collaboration 2011/June/15, KEK Physics Seminar

T2K Collaboration





International collaboration (~500 members, 59 institutes, 12 countries)

T2K (Tokai-to-Kamioka) experiment



T2K Main Goals:

\star Discovery of $v_{\mu} \rightarrow v_{e}$ oscillation (v_{e} appearance)

\star Precision measurement of v_{μ} disappearance

CP odd term in $v_{\mu} \rightarrow v_e$ **prob.** $\propto \sin \delta \cdot s_{12} \cdot s_{23} \cdot s_{13}$

Overview of this talk

- 1. Introduction of T2K experiment
- 2. Search for v_e appearance with 1.43 x 10²⁰ protons on target (p.o.t.)
 - Analysis overview
 - v_e selection criteria
 - The expected number of events at Far detector
 - Systematic uncertainty
 - Observation at Far detector & Results
- 3. Conclusion

(Previous results w/ 0.32 x 10²⁰ p.o.t.)

Physics Motivation of ν_e appearance

\star discovery of $v_{\mu} \rightarrow v_{e}$

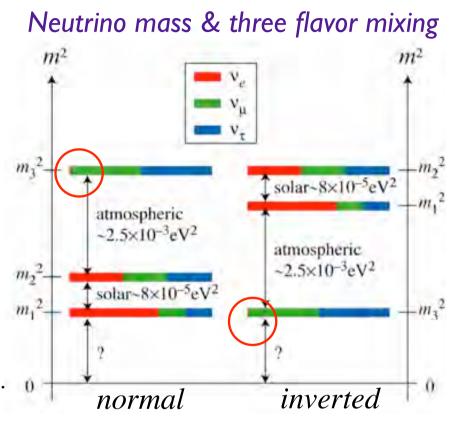
Direct detection of neutrino flavor mixing in "appearance" mode

Determine θ₁₃

The last mixing angle θ_{13} can be determined by $v_{\mu} \rightarrow v_{e}$

Open a possibility to measure CP violation in lepton sector

CPV term in P($v_{\mu} \rightarrow v_{e}$) $\propto sin\theta_{12}sin\theta_{13}sin\theta_{23}sin\delta$



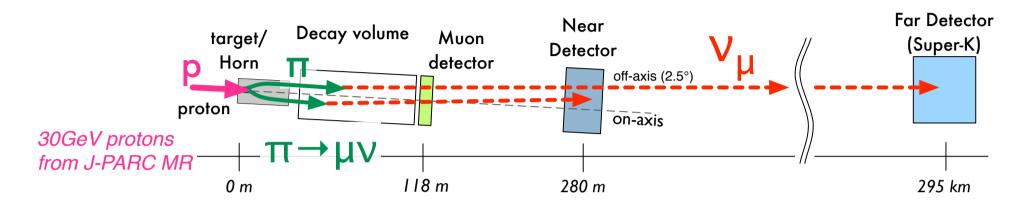
 $\begin{array}{ll} \mbox{Mixing angle: θ_{12}, θ_{23}, θ_{13}}\\ \theta_{12} = 34^\circ \pm 3^\circ & \theta_{23} = 45^\circ \pm 5^\circ \end{array}$

Last unknown mixing angle θ₁₃

 $sin^2 2\theta_{13} < 0.15$ at 90% C.L.

CHOOZ (reactor exp.) and MINOS (accelerator exp.)

Design Principle of T2K



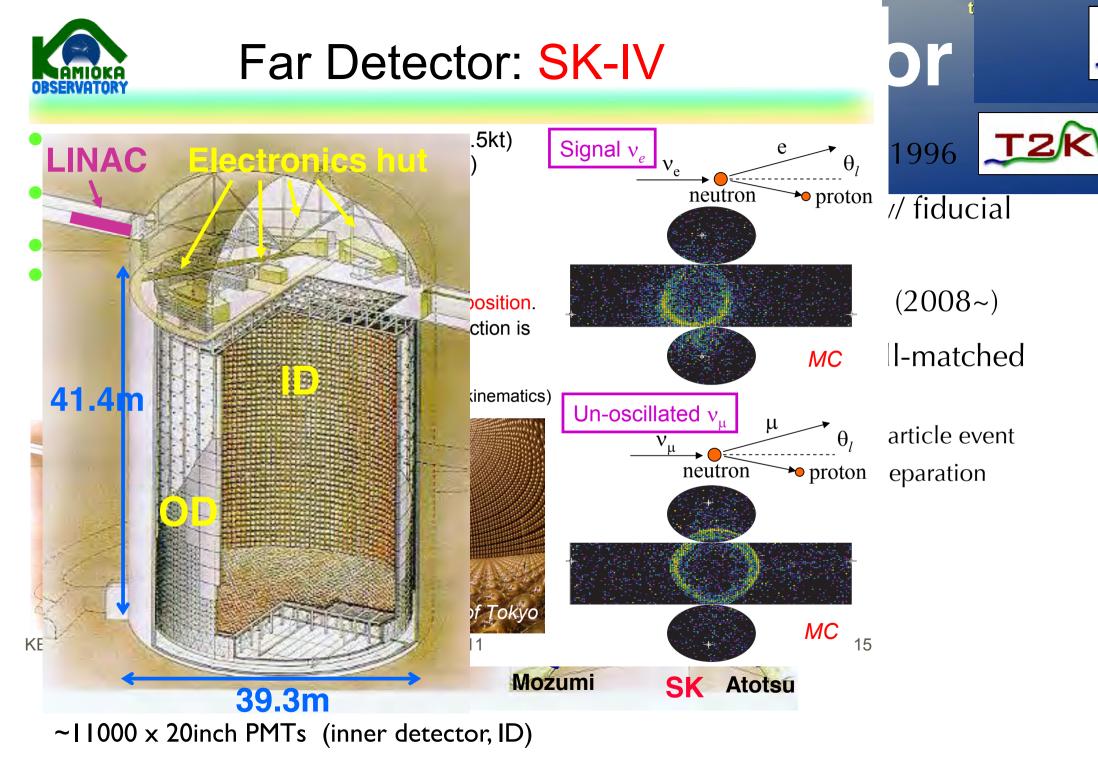
Super-Kamiokande(SK) as far neutrino detector

- Excellent performance for single particle event
 - $v_e + n \rightarrow e + p$ (T2K v_e signal)
 - This event is dominant at sub GeV beam
- Need to reduce high energy tail (reduce background)
- Need high intensity

 \rightarrow Off-axis beam (The first operational long-baseline off-axis \vee beam)

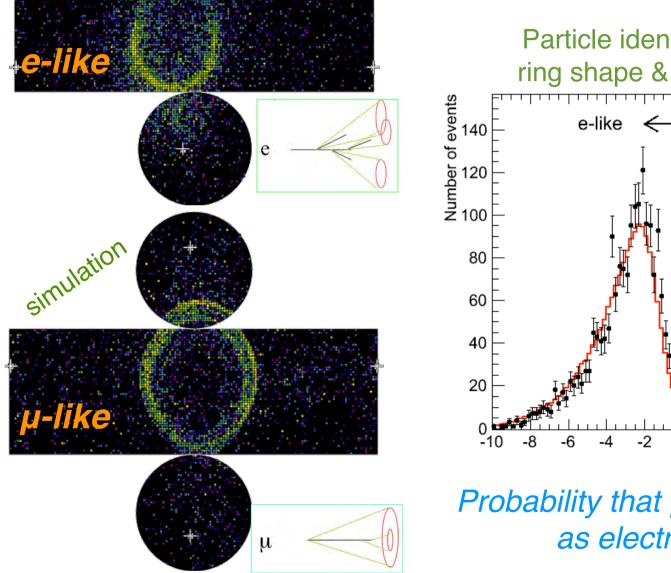
e

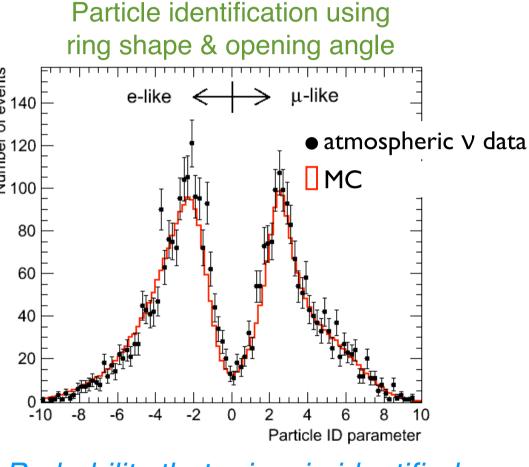
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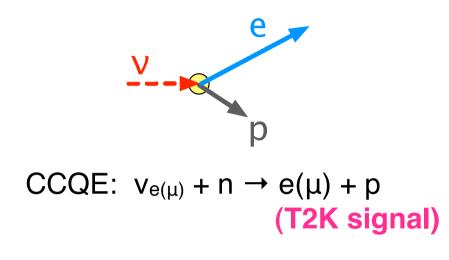
Electron-like and muon-like event at SK





Probability that μ is mis-identified as electron is ~1%

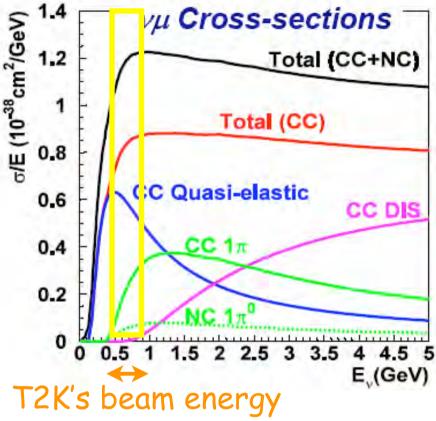
Charged Current Quasi-elastic (CCQE) interactions dominate at sub GeV



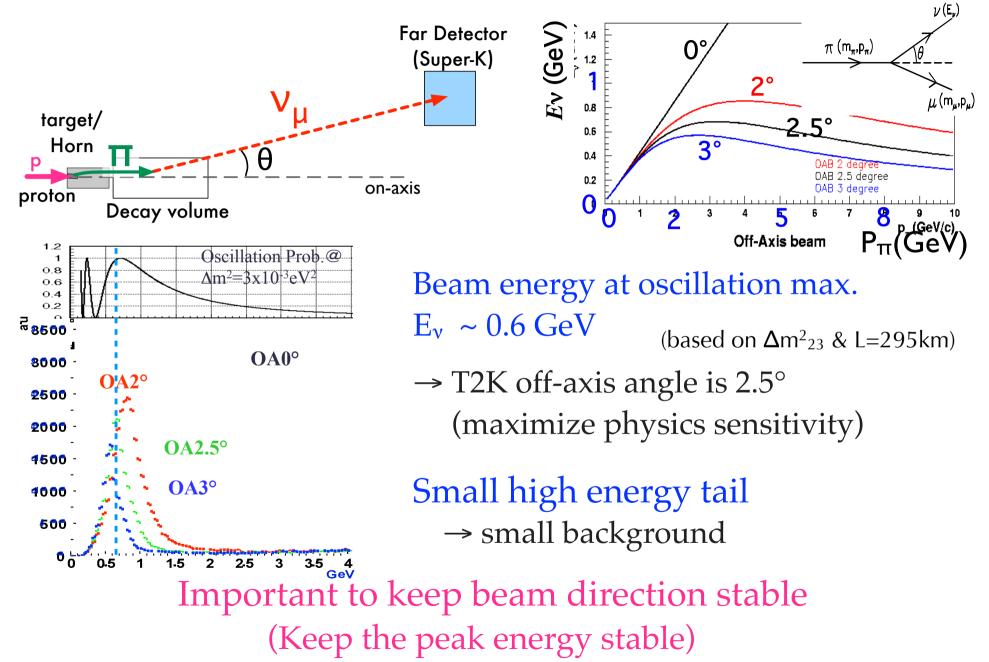
v interactions at high energy cause background events in T2K (e.g. NC1 π^0 is one of v_e background)

 \rightarrow need to reduce high energy \vee

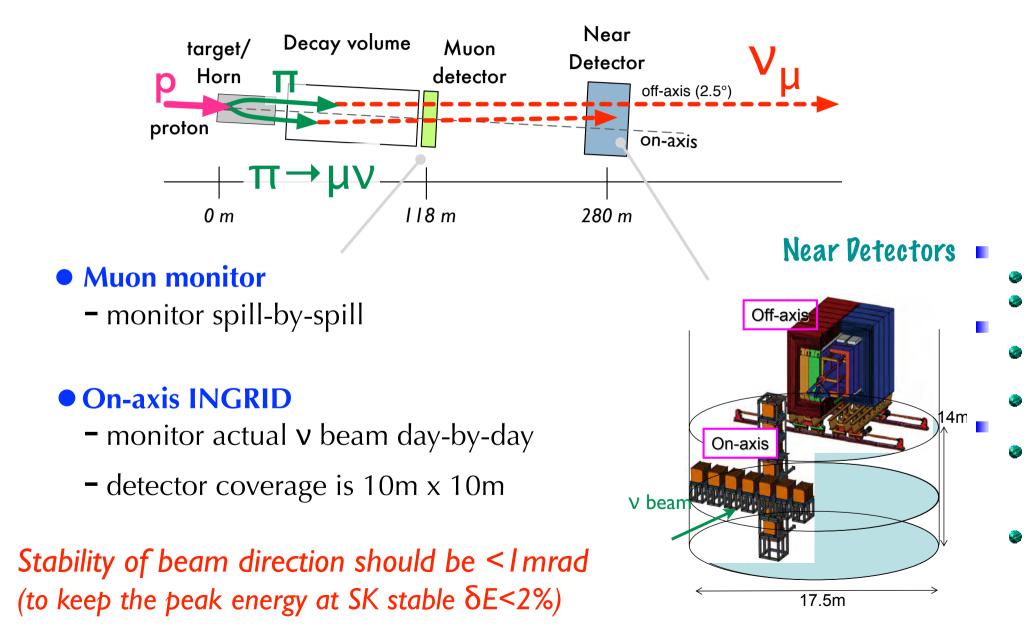




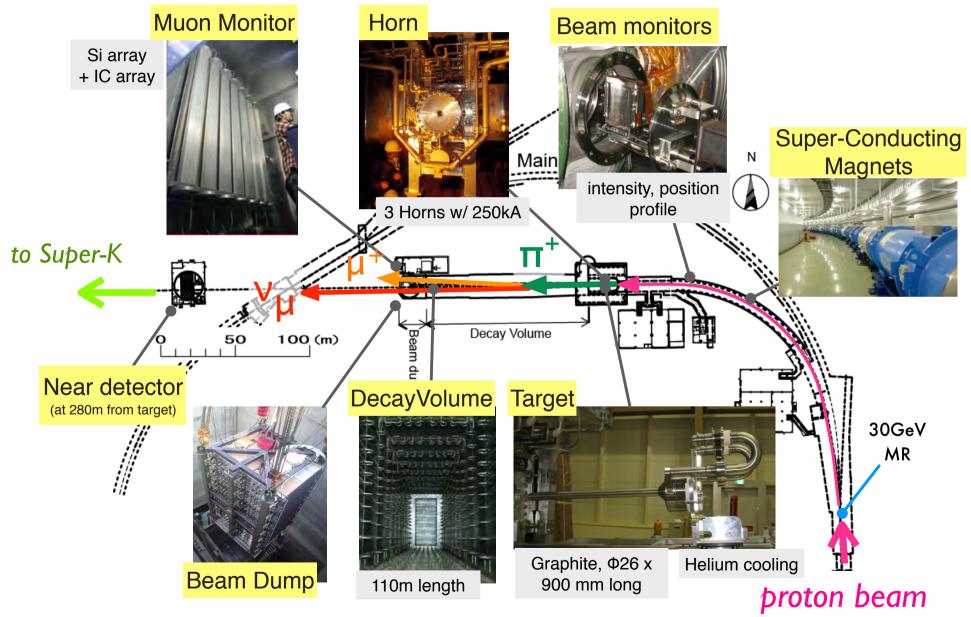
Off-axis beam : intense & narrow-band beam



Monitor beam direction and intensity



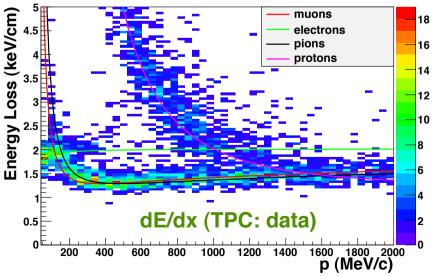
J-PARC Neutrino beam facility



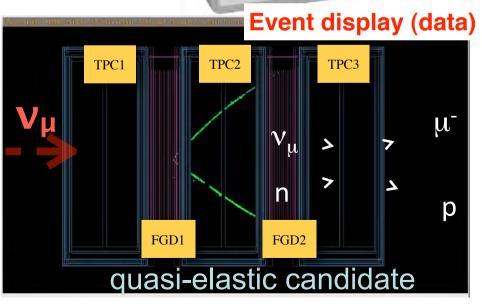
Off-axis Near Detector (ND280)

v_µ CC events rate measurement in present analysis

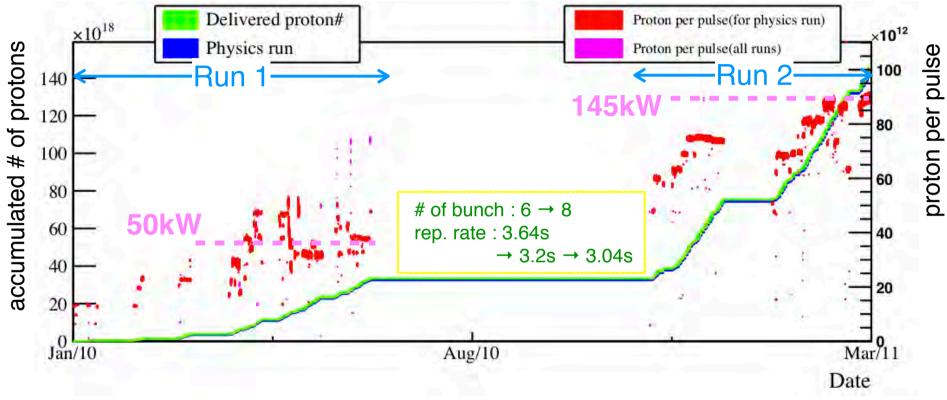
- 0.2 T UA1 magnet
- Fine Grained Detector (FGD)
 - scintillator bars target (water target in FGD2)
 - 1.6ton fiducial mass for analysis
- > Interviewion Chambers (TPC)
 - better than 10% dE/dx resolution
 - 10% momentum resolution at 1GeV/c







Total # of protons used for analysis



Run 1 (Jan. '10 - June '10)

- 3.23 x 10^{19} p.o.t. for analysis
- 50kW stable beam operation

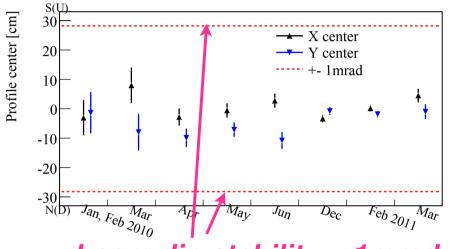
Run 2 (Nov. '10 - Mar. '11)

- 11.08 x 10¹⁹ p.o.t. for analysis
- ~145kW beam operation

Total # of protons used for this analysis is 1.43 x 10²⁰ pot 2% of T2K's final goal and ~5 times exposure of the previous report

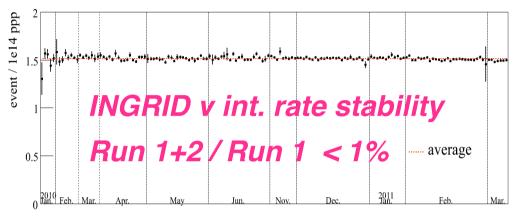
v beam stability

Stability of v beam direction (INGRID)

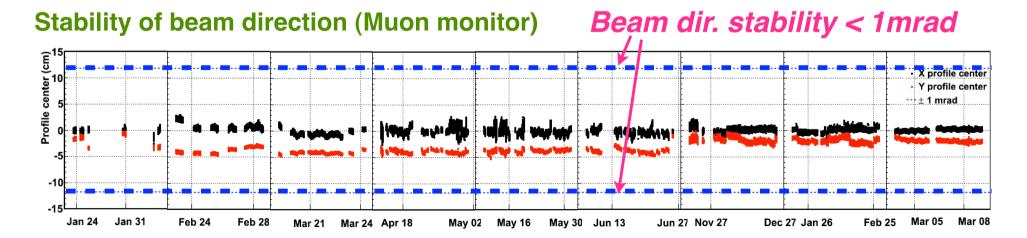


v beam dir. stability < 1mrad

Stability of v interaction rate normalized by # of protons (INGRID)



integrated day(1 data point / 1 day)



Search for v_e appearance

Analysis overview

- 1. Apply $\nu_{\rm e}$ selection criteria to the events at far detector (SK)
- 2. Compare the observed number of events and the expected number of events (for $\sin^2 2\theta_{13}=0$)
 - \rightarrow search for v_e appearance

Contents in this section

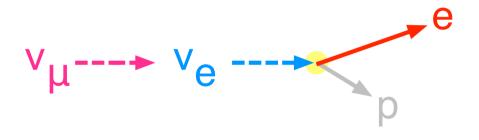
- \Rightarrow v_e selection criteria
- The expected number of events at Far detector using *Hadron (pion) production measurement* & ND event rate measurement
- ∻ Systematic uncertainty
- * Observation at Far detector & Results

v_e selection criteria

- The expected number of events at Far detector
- Systematic uncertainty
- Observation at Far detector & Results

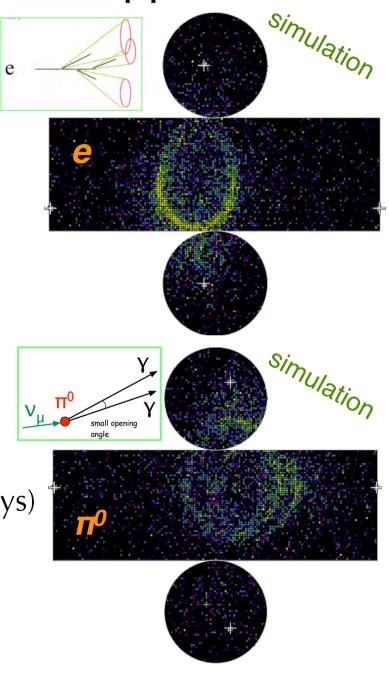
T2K Signal & Background for $\nu_{\rm e}$ appearance

- Signal = **single electron event**
 - oscillated $\nu_{\rm e}$ interaction :



 $CCQE : v_e + n \rightarrow e + p$ (dominant process at T2K beam energy)

- Background
 - intrinsic $\nu_{\rm e}$ in the beam (from $\mu,$ K decays)
 - π^0 from NC interaction



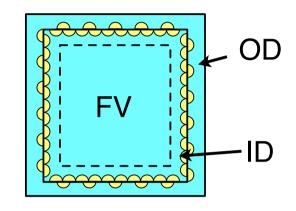
v_e selection at far detector (SK)

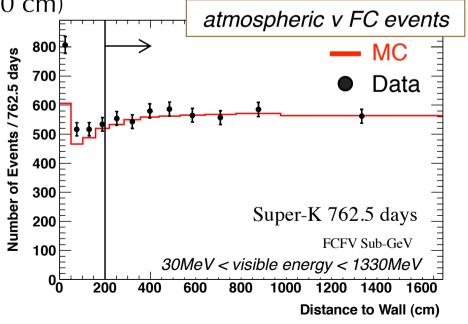
The selection criteria were optimized for initial running condition

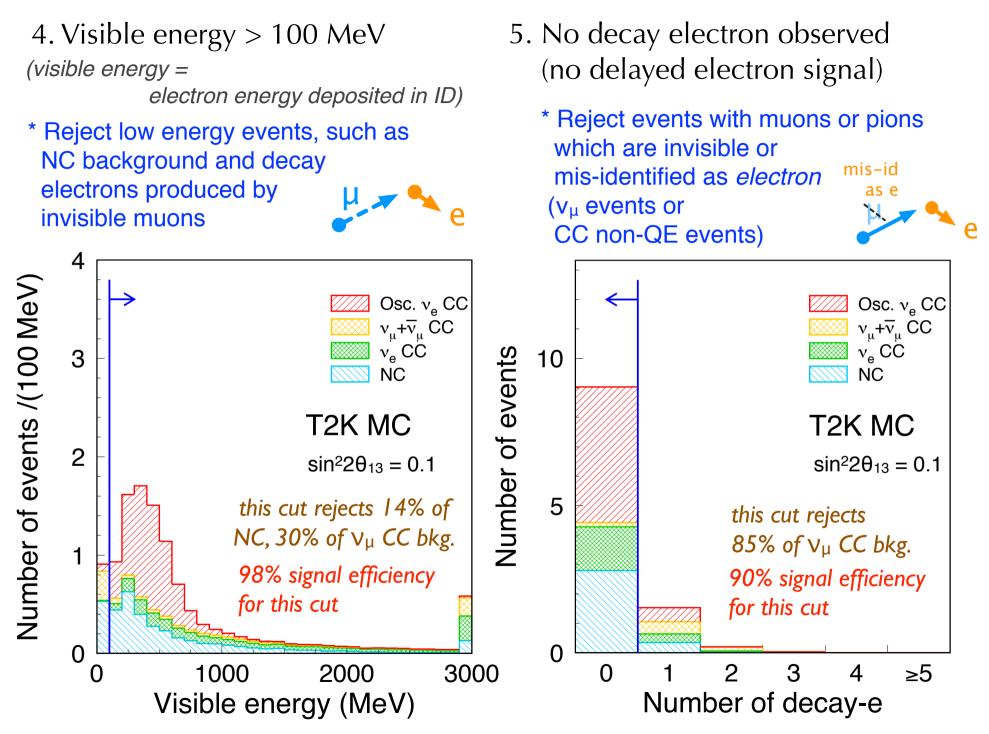
The selection criteria were fixed before data taking started to avoid bias

7 selection cuts

- 1. T2K beam timing & Fully contained (FC) (synchronized with the beam timing, no activities in the OD)
- 2. In fiducial volume (FV) (distance btw recon. vertex and wall > 200 cm)
- * Events too close to the wall are difficult to accurately reconstruct vertex
- * Reject events which are originated outside the ID
- * Define FV 22.5kton
- 3. Single electron (# of ring is one & e-like)



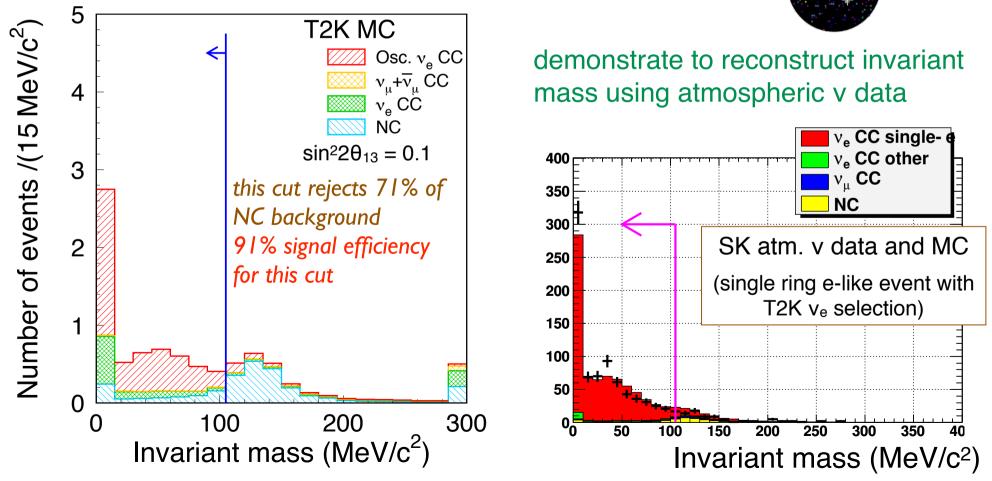




6. Reconstructed invariant mass $(M_{inv}) < 105 \text{ MeV/c}^2$

* Suppress NC π⁰ background

Find 2nd e-like ring by forcing to fit light pattern under the 2 e-like rings assumption, and then ⁰10 -8 reconstruct invariant mass of these 2 e-like rings

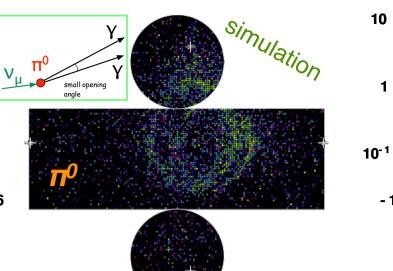


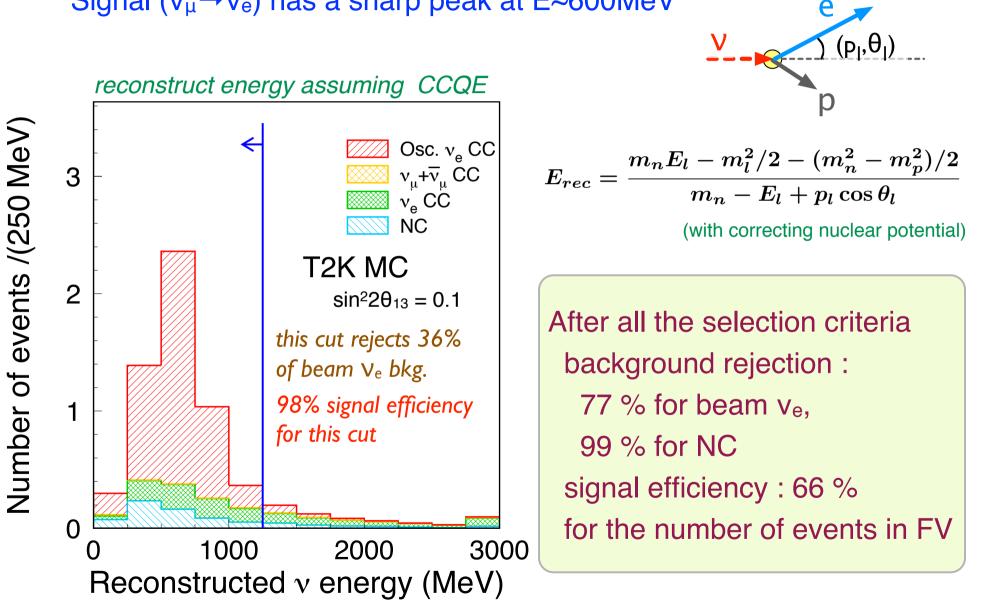
100

80

60

40





- 7. Reconstructed energy $(E_{rec}) < 1250 \text{ MeV}$
 - * Reject intrinsic beam ve backgrounds at high energy
 - * Signal ($v_{\mu} \rightarrow v_{e}$) has a sharp peak at E~600MeV

\checkmark v_e selection criteria

The expected number of events at Far detector with 1.43 x 10²⁰ p.o.t.

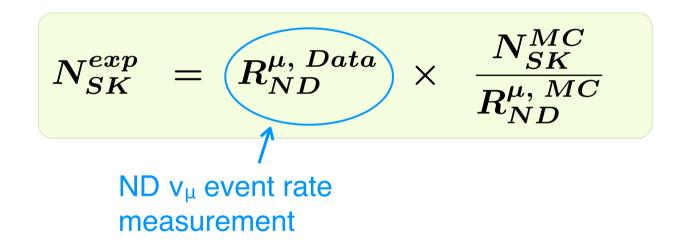
Systematic uncertainty

Observation at Far detector & Results

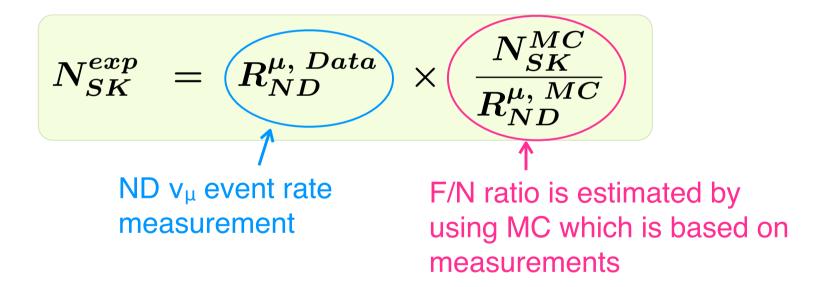
The number of signal and background events are derived by the # of observed v_{μ} event rate at near detector ($R^{\mu,Data}_{ND}$) and the ratio of the expected events at the far detectors and the expected event rate at the near detector (F/N ratio)

$$N_{SK}^{exp} ~=~ R_{ND}^{\mu, ~Data} ~ imes ~~ rac{N_{SK}^{MC}}{R_{ND}^{\mu, ~MC}}$$

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$$N_{SK}^{exp} \;=\; \left(R_{ND}^{\mu,\;Data}
ight) imes \left(rac{N_{SK}^{MC}}{R_{ND}^{\mu,\;MC}}
ight)$$

ND v_{μ} event rate

Measurement of the number of inclusive v_{μ} charged-current events in ND per p.o.t. using data collected in Run 1 (2.88 x 10¹⁹ p.o.t.)

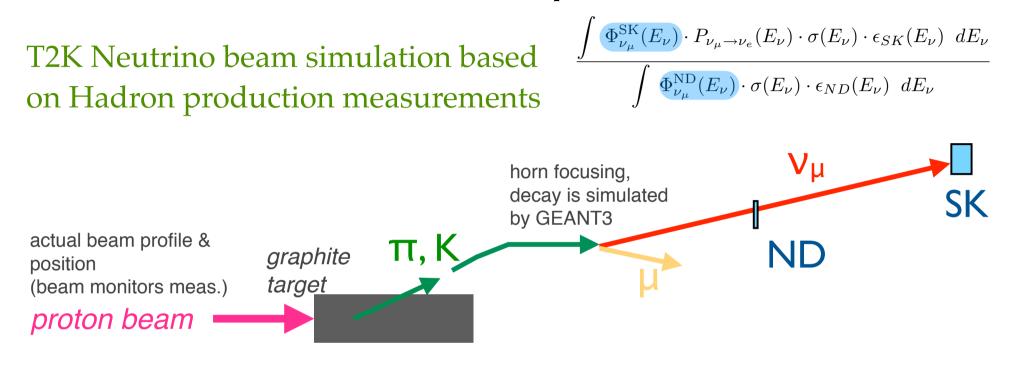
Stability of the beam event rate is confirmed by INGRID measurement *INGRID v int. rate stability Run 1+2/Run 1 < 1%*

F/N ratio for ve signal event

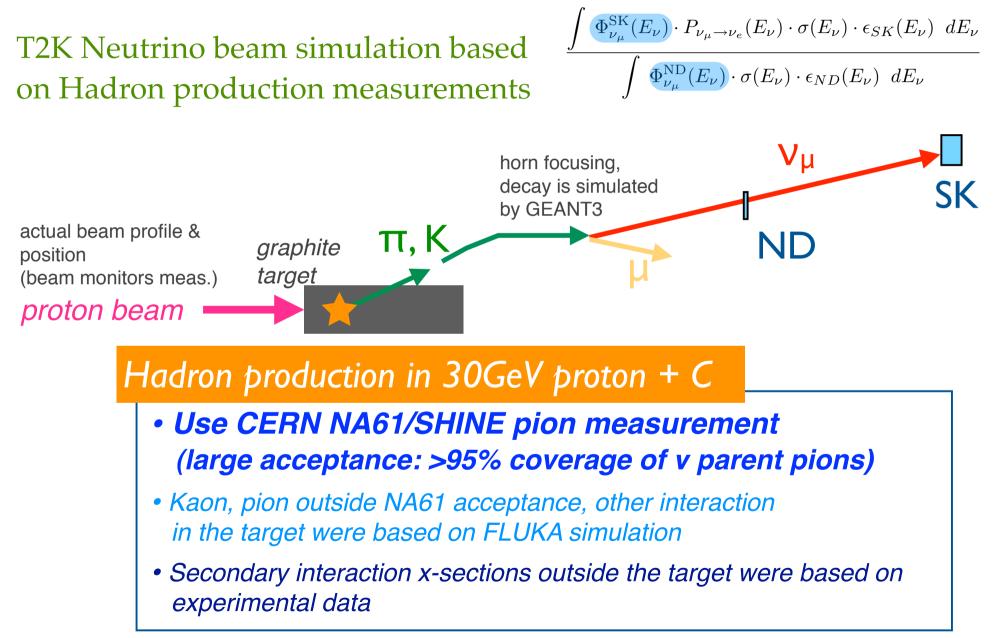
(flux) x (osc. prob.) x (x-section) x (efficiency) x (det. mass)

$$\frac{N_{SK \nu_e sig.}^{MC}}{R_{ND}^{\mu, MC}} = \frac{\int \Phi_{\nu_{\mu}}^{SK}(E_{\nu}) \cdot P_{\nu_{\mu} \to \nu_e}(E_{\nu}) \cdot \sigma(E_{\nu}) \cdot \epsilon_{SK}(E_{\nu}) \ dE_{\nu}}{\int \Phi_{\nu_{\mu}}^{ND}(E_{\nu}) \cdot \sigma(E_{\nu}) \cdot \epsilon_{ND}(E_{\nu}) \ dE_{\nu}} \cdot \frac{M^{SK}}{M^{ND}} \cdot \text{POT}^{SK}$$

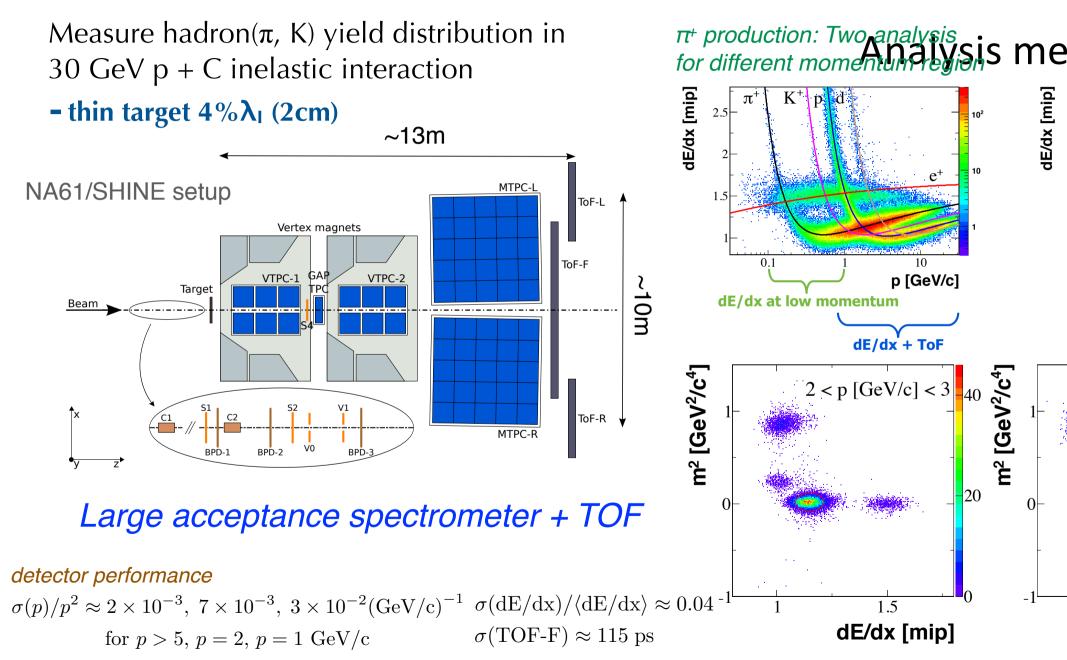
Neutrino flux prediction



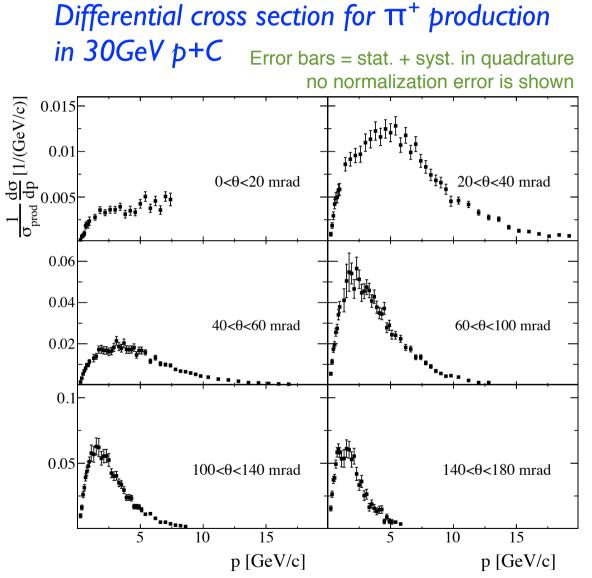
Neutrino flux prediction



CERN NA61/SHINE measurement



Results of pion production from thin target (2007 data)



N.Abgrall et al., arXiv:1102.0983 [hep-ex] submitted to Phys.Rev.C (2011)

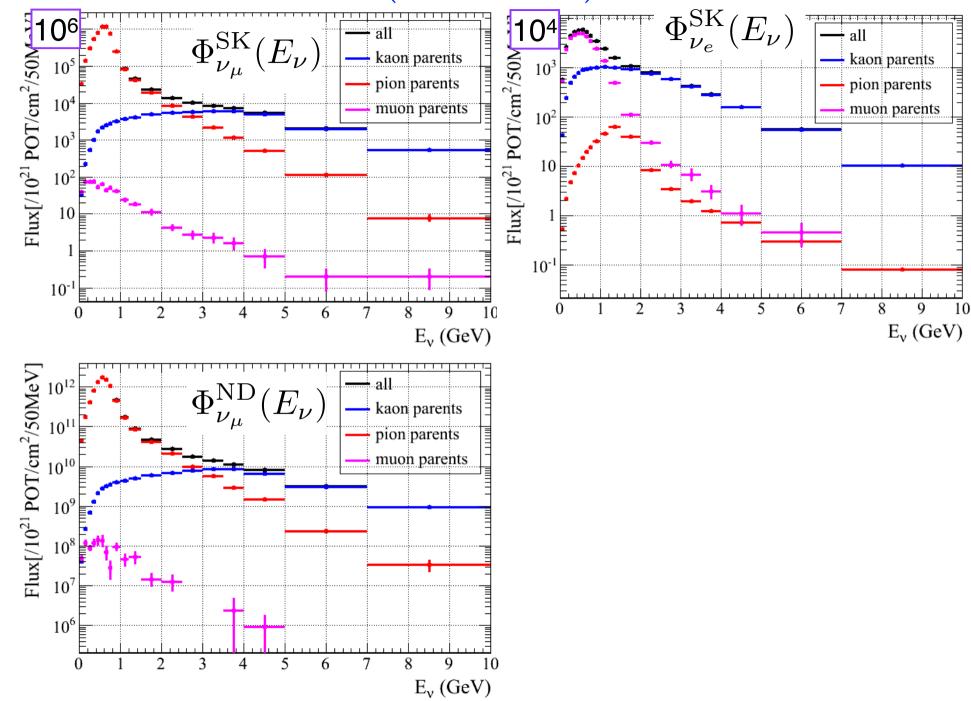
Systematic uncertainty was evaluated in each (p,θ) bin typically 5-10%

The normalization uncertainty is 2.3% on the overall (p, θ)

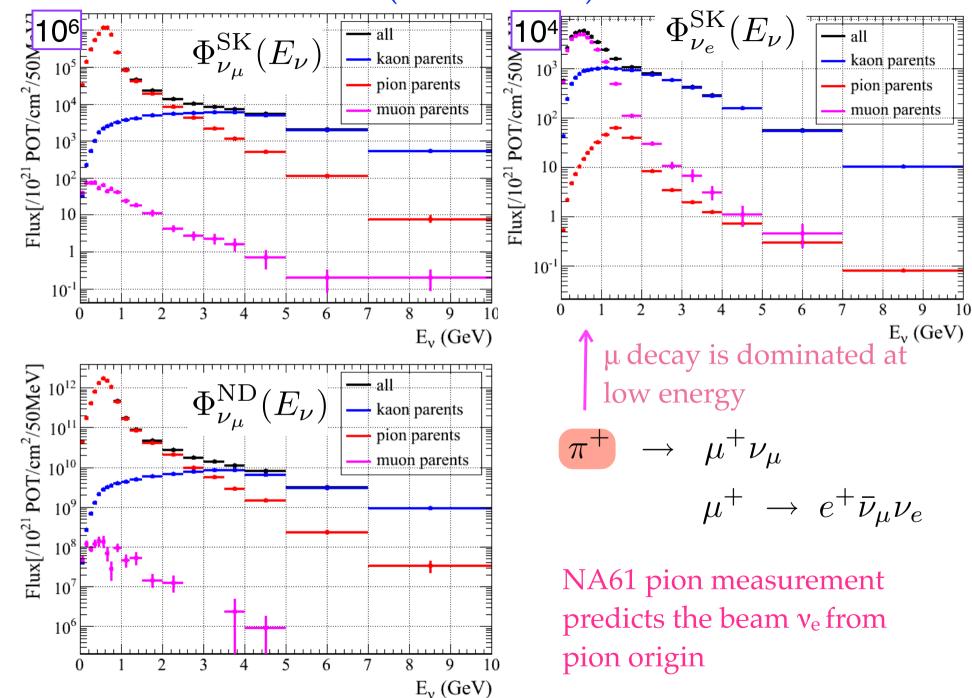
→ Propagate the systematic uncertainty in each (p, θ) bin into the expected number of events in T2K

→ Input to T2K neutrino beam simulation

Predicted neutrino flux (center value)

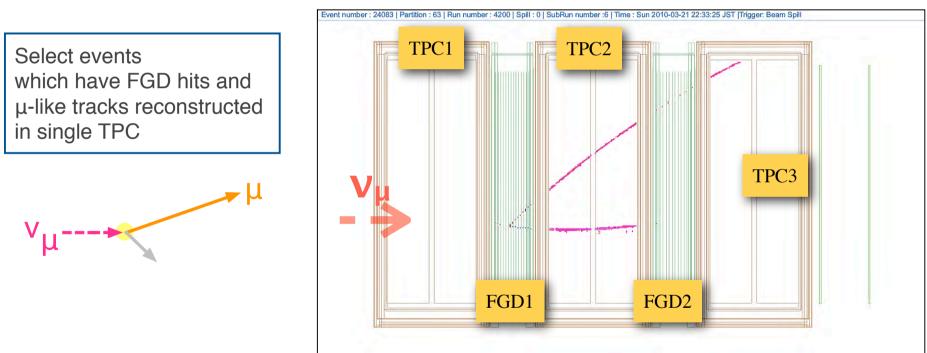


Predicted neutrino flux (center value)



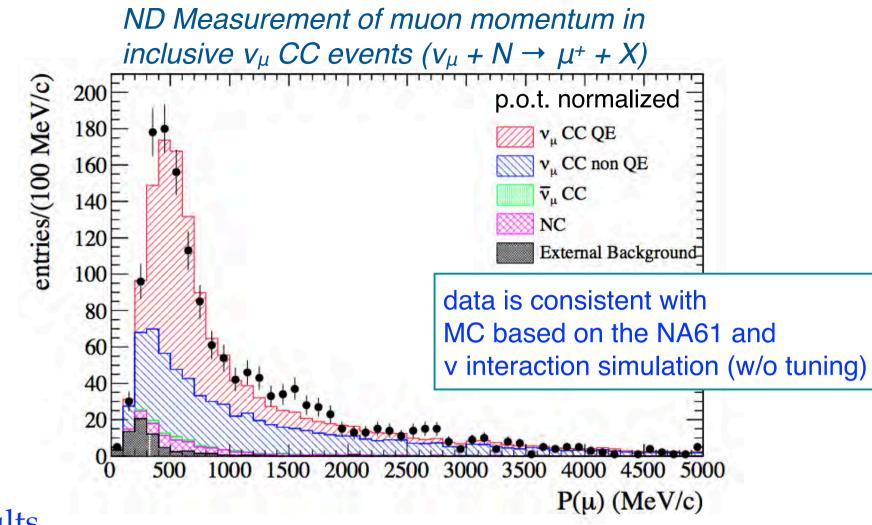
ν_{μ} interaction rates at near detector

• Measure # of inclusive v_{μ} charged current interaction (N^{Data}_{ND})



High purity : 90% v_µ Charged Current int. (50% CCQE)

Event display (data)



$$\begin{aligned} R_{ND}^{\mu, \ Data} &= 1529 \text{ events } / \ 2.9 \times 10^{19} \text{ p.o.t.} \\ \\ \frac{R_{ND}^{\mu, \ Data}}{R_{ND}^{\mu, \ MC}} &= 1.036 \pm 0.028(\text{stat.})^{+0.044}_{-0.037}(\text{det. syst.}) \pm 0.038(\text{phys. syst.}) \end{aligned}$$

Intrinsic Beam v_e background at Far detector

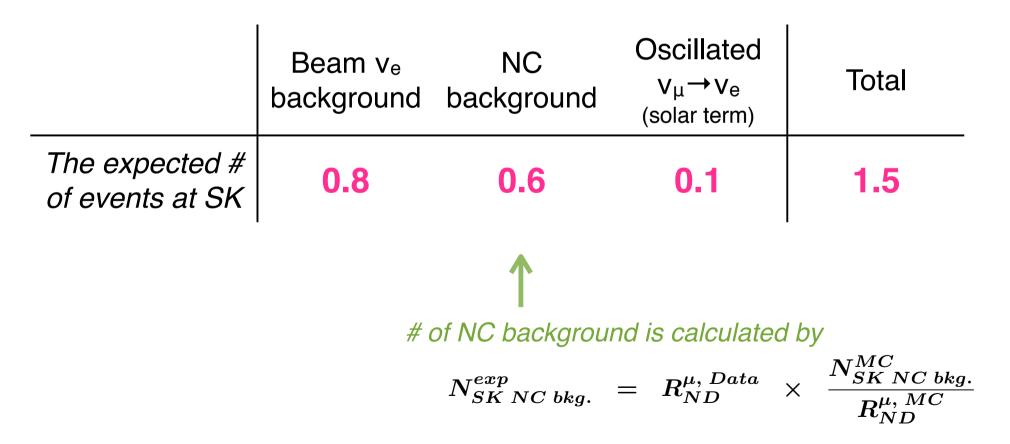
- The number of beam v_e background events at far detector is predicted using the v beam simulation based on NA61 measurements (pion) and FLUKA (kaon)
 - ND measurements (μ momentum and event rate) are consistent with MC based on the ν beam simulation

$$N_{SK\ beam\ \nu_e\ bkg.}^{exp} = R_{ND}^{\mu,\ Data} \times \underbrace{\frac{N_{SK\ beam\ \nu_e\ bkg.}^{MC}}{R_{ND}^{\mu,\ MC}}}_{R_{ND}^{\mu,\ MC}} + \underbrace{\frac{\int \Phi_{\nu_e}^{SK}(E_{\nu}) \cdot P_{\nu_e \to \nu_e}(E_{\nu}) \cdot \sigma(E_{\nu}) \cdot \epsilon_{SK}(E_{\nu})\ dE_{\nu}}{\int \Phi_{\nu_{\mu}}^{NC}(E_{\nu}) \cdot \sigma(E_{\nu}) \cdot \epsilon_{ND}(E_{\nu})\ dE_{\nu}}} \cdot \frac{M^{SK}}{M^{ND}} \cdot \text{POT}^{SK}$$

The expected number of events for $\sin^2 2\theta_{13}=0$

The expected number of events with 1.43 x 10²⁰ p.o.t.

 $N^{exp}_{SK tot.} = 1.5 \text{ events}$



\checkmark v_e selection criteria

The expected number of events at Far detector

Systematic uncertainty

Observation at Far detector & Results

Systematic uncertainty on N^{exp}_{SK}

	error source	syst. error	
	(1) ν flux	$\pm 8.5\%$	for $sin^2 2\theta_{13}=0$
	(2) ν int. cross section	$\pm 14.0\%$	
	(3) Near detector	$^{+5.6}_{-5.2}\%$	
	(4) Far detector	$\pm 14.7\%$	
	(5) Near det. statistics	$\pm 2.7\%$	
	Total	$^{+22.8}_{-22.7}\%$	
$N^{exp}_{SK} = rac{R^{\mu,\ D}_{ND}}{R^{\mu,\ D}_{ND}}$	$\frac{N_{SK}^{MC}}{R_{ND}^{\mu,\ MC}}$	➡ N ^{exp} SK	=1.5±0.3 events
	$\int \Phi_{\nu_{\mu}(\nu_{e})}^{\rm SK}(E_{\nu})$	$\cdot P_{osc.}(E_{\nu}) \cdot \sigma($	$\left \frac{E_{\nu}}{E_{\nu}} \right \cdot \epsilon_{SK}(E_{\nu}) \ dE_{\nu}$
	$\int \Phi^{ m ND}_{ u_{\mu}}($	$(E_{\nu}) \cdot \frac{\sigma(E_{\nu})}{\sigma(E_{\nu})} \cdot \epsilon_{I}$	$_{ND}(E_{\nu}) \ dE_{\nu}$

Systematic uncertainty on N^{exp}_{SK}

error source	syst. error	
$O(1) \nu$ flux	$\pm 8.5\%$	for $sin^{2}2\theta_{13}=0$
$O(2)$ ν int. cross section	$\pm 14.0\%$	
(3) Near detector	$^{+5.6}_{-5.2}\%$	
O(4) Far detector	$\pm 14.7\%$	
(5) Near det. statistics	$\pm 2.7\%$	
Total	$+22.8 \ \% -22.7 \ \%$	
$N_{SK}^{exp} ~=~ oldsymbol{R}_{ND}^{\mu, ~Data} ~ imes~ rac{N_{SK}^{MC}}{R_{ND}^{\mu, ~MC}}$	➡ N ^{exp} SK	=1.5±0.3 events
$\int \Phi_{\nu_{\mu}(\nu_{e})}^{\rm SK}(E_{\nu})$	$\cdot P_{osc.}(E_{\nu}) \cdot \sigma($	$\left \frac{E_{\nu}}{E_{\nu}} \right \cdot \epsilon_{SK}(E_{\nu}) \ dE_{\nu}$
	$(E_{ u}) \cdot \sigma(E_{ u}) \cdot \epsilon_{I}$	

Neutrino flux uncertainty

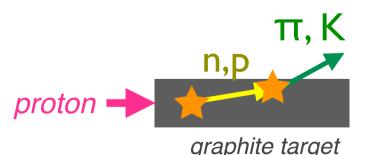
Uncertainties in hadron production and interaction are dominant sources $(2) \ \nu \text{ cross section}$ (3) Near detector (4) Far detector (5) Near det. statistics (5) Near det. statistics

error source

(1) ν flux

Error source

- Pion production
 - NA61 systematic uncertainty in each pion's (p, θ) bin
- Kaon production
 - Used model (FLUKA) is compared with the data(Eichten et. al.) in each kaon's (p, θ) bin
- Secondary nucleon production
 - Used model (FLUKA) is compared with the experimental data
- Secondary interaction cross section
 - Used model (FLUKA and GCALOR) is compared with the experimental data of interaction x-section (π, K and nucleon)



Summary of v flux uncertainties on N^{exp}_{SK} for $sin^22\theta_{13}=0$

	N_{SK}^{exp}	=	$R_{ND}^{\mu,\ Data}$	$ imes ~~ rac{N^{MC}_{SK}}{R^{\mu,~MC}_{ND}}$
Error source			$\frac{N_{SK}^{MC}}{R_{ND}^{\mu,\ MC}}$	_
Pion production			2.5%	
Kaon production			7.6%	Hadron
Nucleon production			1.4%	<i>production</i>
Production x-section			0.7%	& interaction
Proton beam position/profile			2.2%	
Beam direction measurement			0.7%	
Target alignment			0.2%	
Horn alignment			0.1%	
Horn abs. current			0.3%	
Total			8.5%)

The uncertainty on N^{exp}_{SK} due to the beam flux uncertainty is **8.5**%

 ΛI

Summary of v flux uncertainties on N^{exp}_{SK} for $sin^22\theta_{13}=0$

		$N^{exp}_{SK}\;=\;$	$R_{ND}^{\mu,\ Data}$	$ imes \; rac{N_{SK}^{MC}}{R_{ND}^{\mu,\;MC}}$
Error source	$R_{ND}^{\mu,\;MC}$	N_{SK}^{MC}	$\frac{N_{SK}^{MC}}{R_{ND}^{\mu, \ MC}}$	
Pion production	5.7%	6.2%	2.5%	
Kaon production	10.0%	11.1%	7.6%	Hadron
Nucleon production	5.9%	6.6%	1.4%	production
Production x-section	7.7%	6.9%	0.7%	& interaction
Proton beam position/profile	2.2%	0.0%	2.2%	
Beam direction measurement	2.7%	2.0%	0.7%	
Target alignment	0.3%	0.0%	0.2%	
Horn alignment	0.6%	0.5%	0.1%	
Horn abs. current	0.5%	0.7%	0.3%	
Total	15.4%	16.1%	8.5%)

The uncertainty on N^{exp}_{SK} due to the beam flux uncertainty is 8.5% Error cancellation works for some beam uncertainties

NTMC

v int. cross section uncertainty

Evaluate uncertainty on F/N ratio by varying the cross section within its uncertainty

N	lain v interaction in each event category \sim
	NC background : NC1 π^0
	Beam v_e background : v_e CCQE
	Signal : v _e CCQE
	ND CC event : CCQE(50%)
	CC1π(23%)

	Cross section uncertainty
Process	relative to the CCQE total x-section
CCQE	energy dependent ($\sim \pm 7\%$ at 500 MeV)
CC 1π	$30\%~(E_{ u} < 2~{ m GeV}) - 20\%~(E_{ u} > 2~{ m GeV})$
CC coherent π^{0}	100% (upper limit from [30])
CC other	$30\% (E_{\nu} < 2 \text{ GeV}) - 25\% (E_{\nu} > 2 \text{ GeV})$
NC $1\pi^0$	$30\% (E_{\nu} < 1 \text{ GeV}) - 20\% (E_{\nu} > 1 \text{ GeV})$
NC coherent π	30%
NC other π	30%
Final State Int	. energy dependent ($\sim \pm 10\%$ at 500 MeV)
TT (' '	

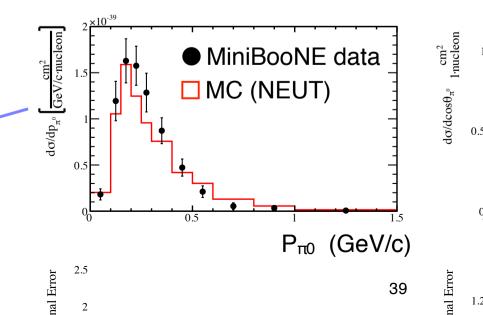
Uncertainty of $\sigma(v_e) / \sigma(v_\mu) = \pm 6\%$

error source

- (1) ν flux
- (2) ν cross section
- (3) Near detector
- (4) Far detector
- (5) Near det. statistics

$$\frac{\int \Phi_{\nu_{\mu}(\nu_{e})}^{\mathrm{SK}}(E_{\nu}) \cdot P_{osc.}(E_{\nu}) \cdot \sigma(E_{\nu}) \cdot \epsilon_{SK}(E_{\nu}) \ dE_{\nu}}{\int \Phi_{\nu_{\mu}}^{\mathrm{ND}}(E_{\nu}) \cdot \sigma(E_{\nu}) \cdot \epsilon_{ND}(E_{\nu}) \ dE_{\nu}}$$

Cross section uncertainties are estimated by Data/MC comparison, model comparison and parameter variation



error source

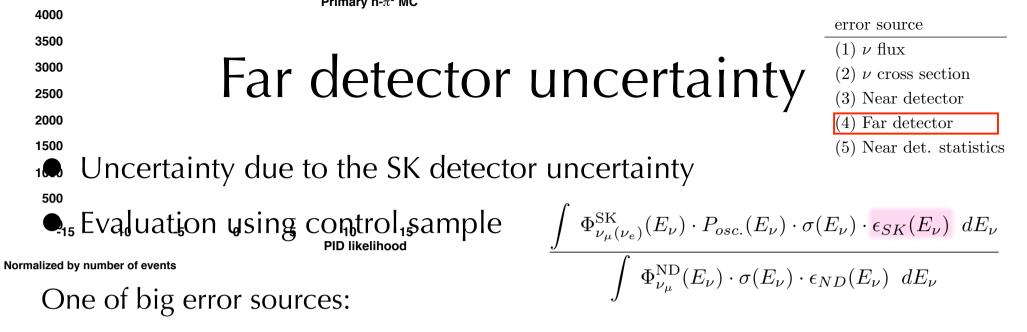
v int. cross section uncertainty on N^{exp}_{SK} for sin²2 θ_{13} =0

(1) ν flux

- (2) ν cross section
- (3) Near detector
- (4) Far detector
- (5) Near det. statistics

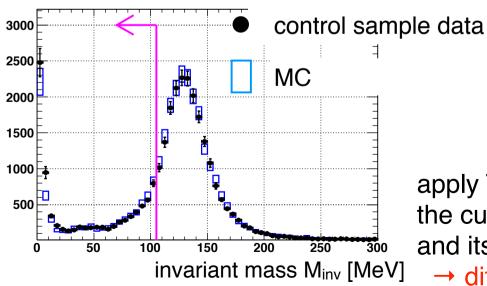
Error source	syst. error on N_{SK}^{exp}	
CC QE shape	3.1%	-
$\mathrm{CC} 1\pi$	2.2%	
CC Coherent π	3.1%	
CC Other	4.4%	
NC $1\pi^0$	5.3%	
NC Coherent π	2.3%	
NC Other	2.3%	
$\sigma(u_e)$	3.4%	Uncertainty in pion's
FSI	10.1%	← final state interaction
Total	14.0%	is dominant

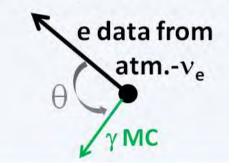
The uncertainty on N^{exp}_{SK} due to the v x-section uncertainty is 14% $(\sin^2 2\theta_{13}=0)$



detection efficiency of NC 1π⁰ background

control sample with one data electron + one simulated γ





apply T2K v_{e} selection and compare the cut efficiency between control sample data and its MC

 \rightarrow difference is assigned as sys. error

Summary of Far detector systematic uncertainty

Error source	$\left \frac{\delta N^{MC}_{SK \ \nu_e \ sig.}}{N^{MC}_{SK \ \nu_e \ sig.}} \right $	$\frac{\delta N^{MC}_{SK\ bkg.\ tot.}}{N^{MC}_{SK\ bkg.\ tot.}}$	
π^0 rejection	-	3.6%	
Ring counting	3.9%	8.3%	Evaluated by
Electron PID	3.8%	8.0%	Evaluated by atmospheric
Invariant mass cut	5.1%	8.7%	v _e enriched data
Fiducial volume cut etc.	1.4%	1.4%	
Energy scale	0.4%	1.1%	
Decay electron finding	0.1%	0.3%	
Muon PID	-	1.0%	
Total	7.6%	15%	

→ The total uncertainty on $N^{MC}_{SK tot.}$ is **14.7** % (sin²2 θ_{13} =0) (uncertainty on the background + solar term oscillated v_e)

Total Systematic uncertainties

Summary of systematic uncertainties on N^{exp}_{SK total.} for sin²20₁₃=0

Error source	$\sin^2 2\theta_{13} = 0$
O(1) Beam flux	$\pm 8.5\%$
$\mathbf{O}(2)$ ν int. cross section	$\pm 14.0\%$
(3) Near detector	$^{+5.6}_{-5.2}\%$
O(4) Far detector	$\pm 14.7\%$
(5) Near det. statistics	$\pm 2.7\%$
Total	+22.80% -22.7%

*cf. sin*²2θ₁₃=0: #sig = 0.1 #bkg = 1.4

 $N^{exp}_{SK tot.} = 1.5 \pm 0.3$ events for sin²2 θ_{13} =0 (w/ 1.43 x 10²⁰ p.o.t.)

Total Systematic uncertainties

Summary of systematic uncertainties on N^{exp}_{SK total.} for sin²20₁₃=0 and 0.1

Error source	$\sin^2 2\theta_{13} = 0$	$\sin^2 2\theta_{13} = 0.1$	cf.
O(1) Beam flux	$\pm 8.5\%$	$\pm 8.5\%$	sin²20 ₁₃ =0: #sig = 0.1 #bkg = 1.4
$O(2) \nu$ int. cross section (3) Near detector	$\pm 14.0\% \\ ^{+5.6}_{-5.2}\%$	$\pm 10.5\% \ +5.6\% \ -5.2\%$	sin ² 2θ ₁₃ =0.1: #sig = 4.1 #bkg = 1.3
O(4) Far detector	$\pm 14.7\%$	$\pm 9.4\%$	
(5) Near det. statistics	$\pm 2.7\%$	$\pm 2.7\%$	
Total	+22.8 % -22.7 %	+17.6 % -17.5 %	
			mall Far det. ainty for signal)

 $N^{exp}_{SK tot.} = 1.5 \pm 0.3$ events for sin²2 θ_{13} =0 (w/ 1.43 x 10²⁰ p.o.t.)

\checkmark v_e selection criteria

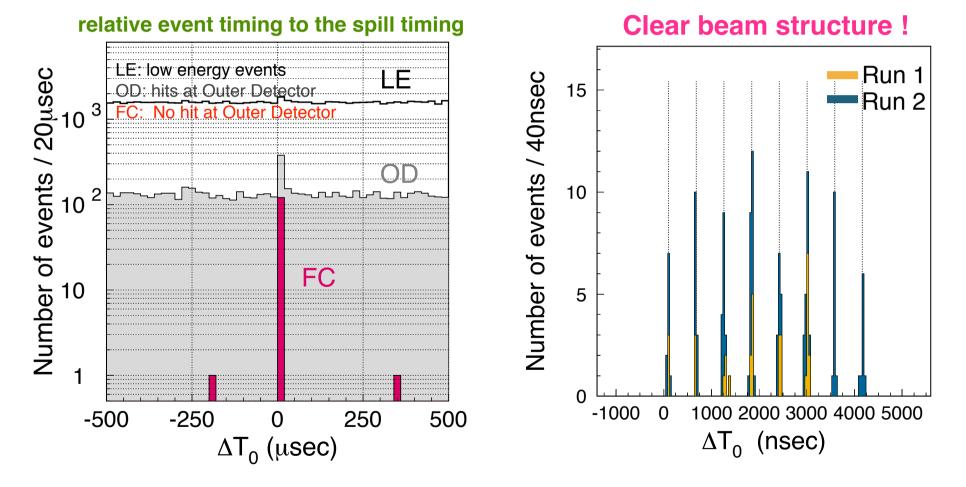
The expected number of events at Far detector

Systematic uncertainty

Observation at Far detector & Results

SK events in beam timing

• Events in the T2K beam timing synchronized by GPS



 $\Delta T_0 = T_{GPS} @SK - T_{GPS} @J-PARC - TOF(~985 \mu sec)$

Number of T2K events at far detector

Number of events in on-timing windows (-2 \sim +10 μ sec)

Class / Beam run	RUN-1	RUN-2	Total	non-beam	
POT (x 10 ¹⁹)	3.23	11.08	14.31	background	
Fully-Contained (FC)	33	88	121	0.023	

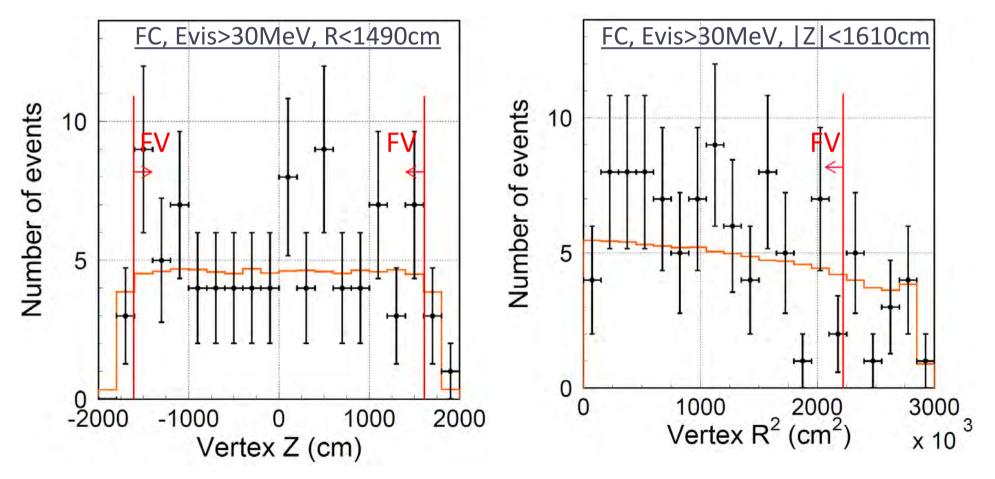
The accidental contamination from atmospheric v background is estimated using the sideband events to be 0.023

Apply ν_e event selection

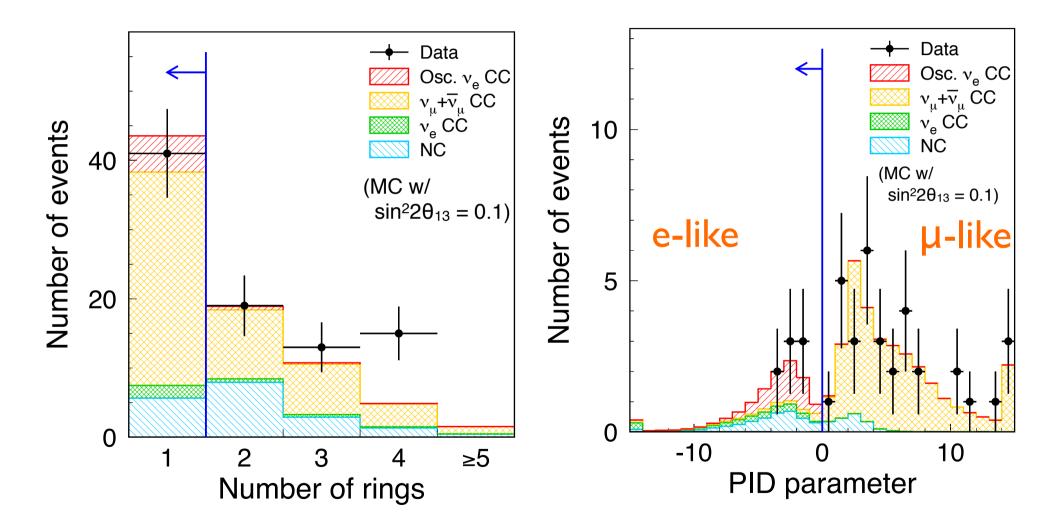
defined before the data collection 6 selection cuts in addition FC cut

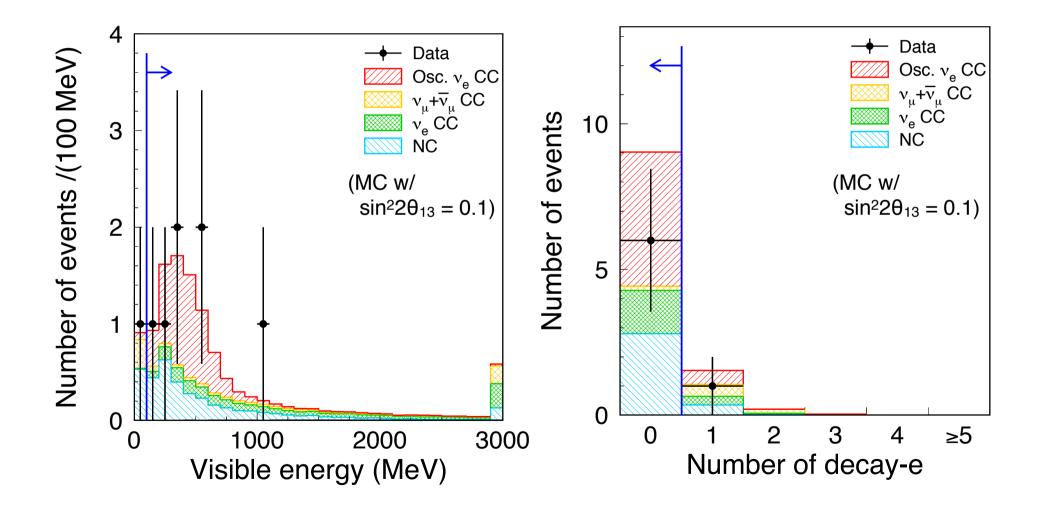
Fiducial volume cut

(distance between recon. vertex and wall > 200cm)

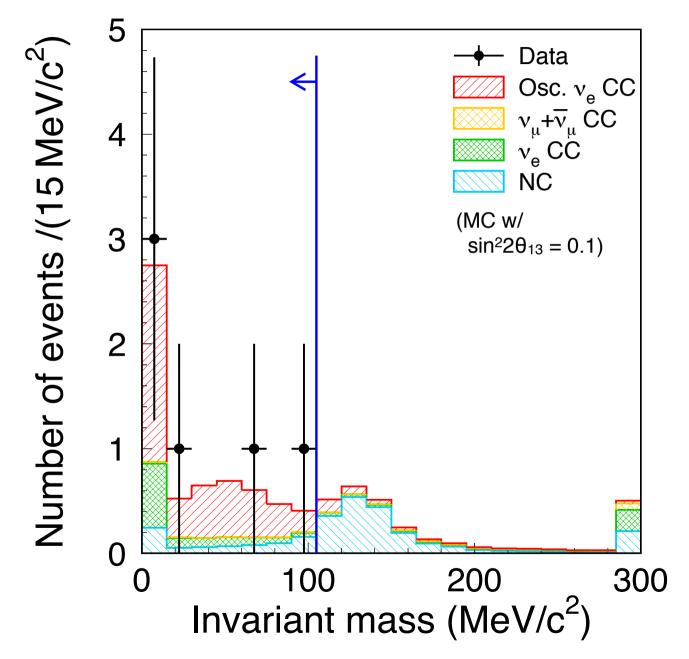


Single electron cut (# of ring is one & e-like)

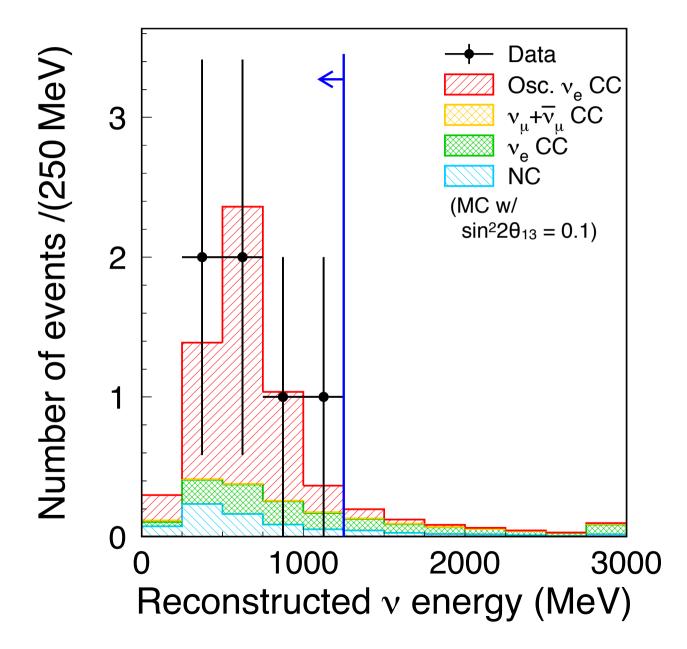




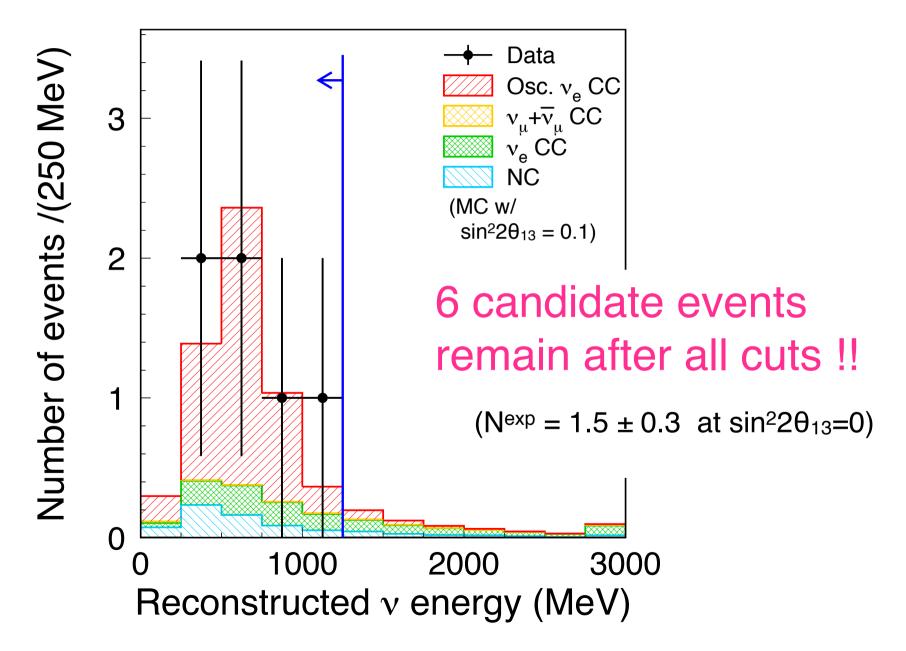
Invariant mass cut ($M_{inv} < 105 \text{ MeV/c}^2$)



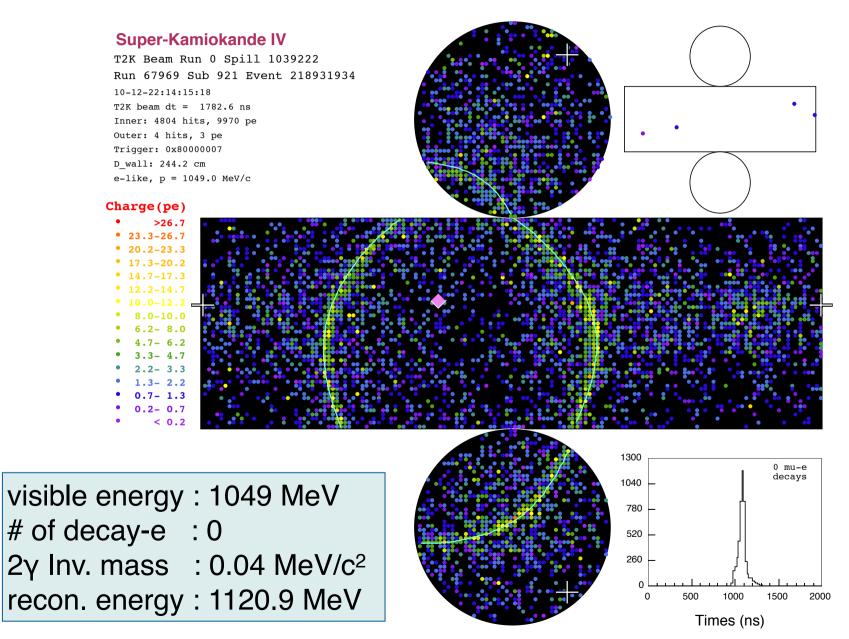
Reconstructed v energy cut ($E_{rec} < 1250 \text{ MeV}$) : Final cut



Reconstructed v energy cut ($E_{rec} < 1250 \text{ MeV}$) : Final cut



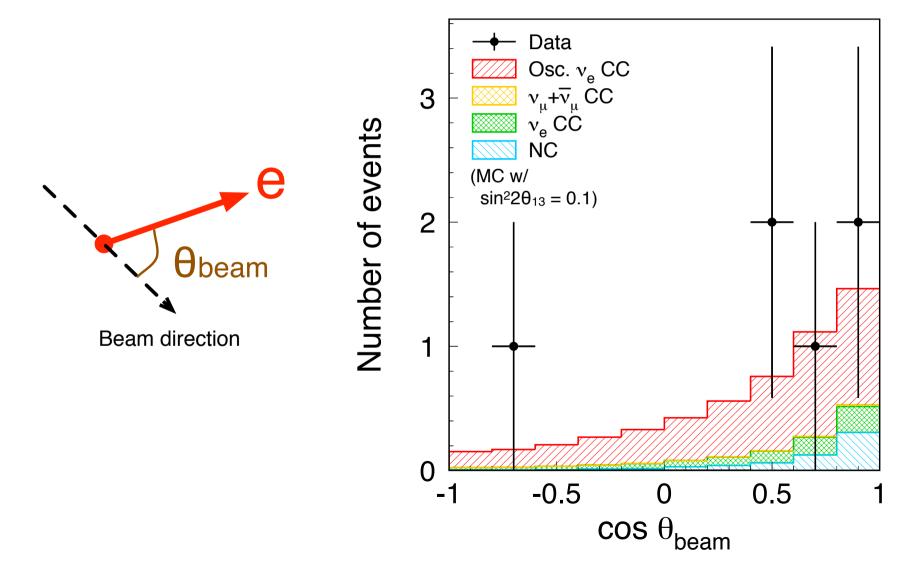
ν_e candidate event



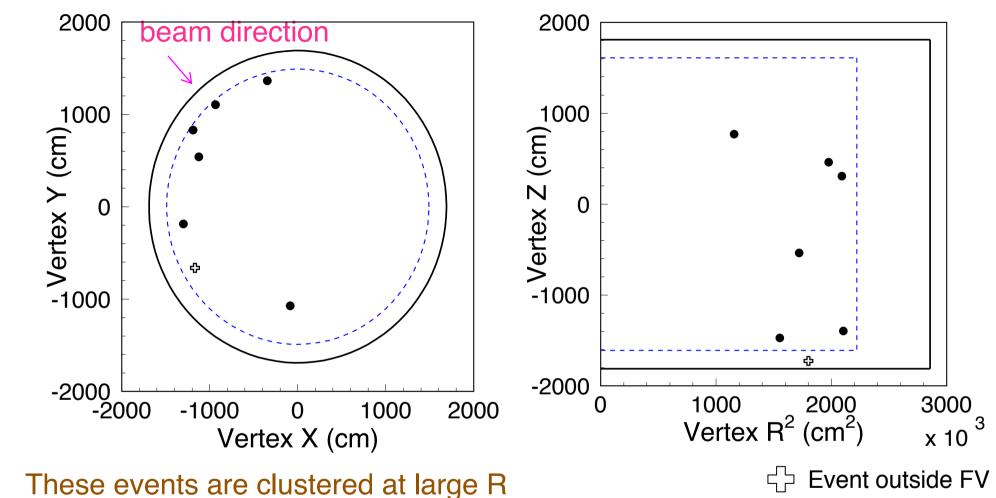
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Further check

Check several distribution of v_e candidate events



Vertex distribution of v_e candidate events



 \rightarrow Perform several checks. for example

- * Check distribution of events outside FV \rightarrow no indication of BG contamination
- * Check distribution of OD events \rightarrow no indication of BG contamination
- * K.S. test on the R² distribution yields a p-value of 0.03

Results for v_e appearance search with 1.43 x 10²⁰ p.o.t.

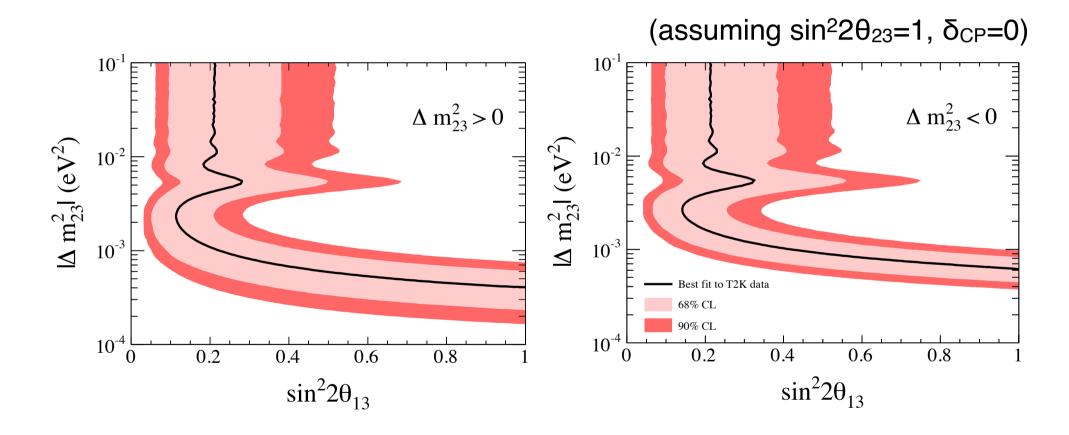
The observed number of events is **6**

The expected number of events is 1.5 ± 0.3

for $sin^22\theta_{13}=0$

Under the θ_{13} =0 hypothesis, the probability to observe six or more candidate events is 0.007 (equivalent to 2.5 σ significance)

Allowed region of $\sin^2 2\theta_{13}$ as a function of Δm^2_{23}



Feldman-Cousins method was used

Allowed region of $sin^2 2\theta_{13}$ as a function of δ_{CP}

(assuming $\Delta m^2_{23}=2.4 \times 10^{-3} \text{ eV}^2$, sin²2 $\theta_{23}=1$) $\Delta m_{23}^2 < 0$ $\Delta m_{23}^2 > 0$ $\pi/2$ $\pi/2$ $\delta_{\rm CP}$ $\delta_{\rm CP}$ 0 0 T2K Best fit to T2K data $-\pi/2$ $-\pi/2$ 1.43×10^{20} p.o.t. 68% CL 90% CL -π -π 0.1 0.2 0.3 0.5 0.1 0.2 0.3 0.5 0.4 0.6 0.4 0.6 0 0 $\sin^2 2\theta_{13}$ $\sin^2 2\theta_{13}$

90% C.L. interval & Best fit point (assuming Δm²₂₃=2.4 x 10⁻³ eV², sin²2θ₂₃=1, δ_{CP}=0)

 $\begin{array}{ll} 0.03 < \sin^2 2\theta_{13} < 0.28 & 0.04 < \sin^2 2\theta_{13} < 0.34 \\ & \sin^2 2\theta_{13} = 0.11 & \sin^2 2\theta_{13} = 0.14 \end{array}$

T2K Next steps

Aim for firmly establishing v_e appearance and better determining the angle θ_{13}

- Resume experiment
 - Recovery works in progress
 - We will resume J-PARC activity including accelerator complex and neutrino facility by December, 2011
 - Neutrino facility will be ready by November
- Analysis improvement
 - New analysis methods using $\nu_{\rm e}$ signal shape (e.g. recon. energy) are under development

Conclusion

- We reported new results on $v_{\mu} \rightarrow v_{e}$ oscillation analysis based on 1.43 x 10²⁰ p.o.t. (2% exposure of T2K's goal)
 - The expected number of events is 1.5 ± 0.3 (sin²2 $\theta_{13} = 0$)
 - 6 candidate events are observed
 - Under θ₁₃=0 hypothesis, the probability to observe 6 or more candidate events is 0.007 (equivalent to 2.5 σ significance)
 - $0.03 (0.04) < \sin^2 2\theta_{13} < 0.28 (0.34) \text{ at } 90\% \text{ C.L. for normal (inverted) hierarchy} \\ (\text{assuming } \Delta \text{m}^2_{23} = 2.4 \text{ x } 10^{-3} \text{ eV}^2, \sin^2 2\theta_{23} = 1, \delta_{\text{CP}} = 0)$

Indication of v_e appearance

submitted to PRL

- Resume experiment as soon as possible and improve analysis method to conclude v_e appearance phenomenon
- v_{μ} disappearance result with 1.43 x 10²⁰ p.o.t. data will be reported this summer